Advances in Image Processing, Analysis and Recognition Technology

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Message from the Collection Editor

The aim of this Topical Collection on "Advances in Image Processing, Analysis and Recognition Technology" is to give researchers the opportunity to provide new trends, latest achievements and research directions as well as to present their current work on the important problem of image processing, analysis and recognition.

Potential topics of interest for this Topical Collection include (but are not limited to) the following areas:

- Image acquisition
- Image quality analysis
- Image filtering, restoration and enhancement
- Image segmentation
- Biomedical image processing
- Color image processing
- Multispectral image processing
- Hardware and architectures for image processing
- Image databases
- Image compression
- Low-level and high-level image description
- Mathematical methods in image processing, analysis and representation
- Artificial intelligence tools in image analysis
- Pattern recognition algorithms applied for images
- Digital watermarking
- Digital photography

Topical Collection

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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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